

<b>Notice of References Cited</b>	Application/Control No. 09/934,426		Applicant(s)/Patent Under Reexamination YAMATANI, WATARU	
	Examiner Olisa Anwah		Art Unit 2614	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0087682	05-2003	Cathey et al.	455/574
*	B	US-2002/0006814	01-2002	Fukunishi, Tatsuya	455/572
*	C	US-5,834,857	11-1998	Abe et al.	307/66
*	D	US-6,223,025	04-2001	Tsukuda, Naoki	340/7.37
*	E	US-6,374,127	04-2002	Park, Jae-Sun	455/572
*	F	US-2001/0017485	08-2001	Yoo, Wan Sik	307/66
*	G	US-5,335,263	08-1994	Tsunehiro et al.	455/572
*	H	US-5,438,696	08-1995	Napoles, Adrian	455/343.6
*	I	US-5,420,576	05-1995	Matai et al.	340/7.43
*	J	US-5,701,597	12-1997	Nakanishi et al.	455/127.1
*	K	US-5,117,449	05-1992	Metroka et al.	455/552.1
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.